Form PTO 1449		U.S. DEPARTMENT PATENT AND TRAD	OF COMMERCE	ATTY DOCKET NO. 246722US2SRD DIV		SERIAL NO.  New DIV Application			
(Modified)		PATENT AND TRAC	DEMARK OFFICE						
				APPLICANT					
LIST OF REFERENCES CITED BY APPLICANT				Koji USUDA, et al.					
				FILING DATE		GROUP			
				Herewith					
				U.S. PATENT DOCUMENTS		L			
				U.S. PATENT DOCUMENTS	· · ·	l aug I			
EXAMINÉR INITIAL			DATE	NAME CLASS		SUB FILING DATE CLASS IF APPROPRIATE			
011	AA	5,847,419	12/08/98	IMAI, et al.					
10/42-A	AB	5,759,898	06/1998	EK, et al.	<u> </u>				
						<u> </u>			
<b>├</b> ─ <i>├</i> ─	AC	5,218,213	06/1993	GAUL, et al.	<del>                                     </del>				
	AD		ļ <del></del>		ļ				
	AE				ļ	ļ			
	AF								
	AG								
	AH	/							
	Al						•		
<del>                                     </del>	AJ								
<del></del>	AK		İ						
<del>                                     </del>	AL						·		
<del></del>	AM	-			†				
<del></del>	AN		1		+				
<del></del>	AIN		1		1	<u>l</u>	****		
		·	FO	REIGN PATENT DOCUMENTS					
		DOCUMENT DATE COUNTRY			TRANSLATION				
		NUMBER	00,12	JOSHIKI		YES NO			
	AO	7-169926	07/04/95	Japan					
	AP	11-121377	04/30/99	Japan					
	AQ	9-321307	12/12/97	Japan					
	AR		<u> </u>						
	AS	<del>-,</del>							
<del> </del>	AT					<del> </del>			
<del>                                     </del>	AU		<del> </del>				<del>  </del>		
<del></del>			ļ	,			<del>-</del>		
	AV		J			<u>.</u>			
	OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)								
		J. WELSER, et al., "STRAIN DEPENDENCE OF THE PERFORMANCE ENHANCEMENT IN STRAINED-SI n-MOSFETS,"							
	AW	IEDM, 1994, pgs. 373	-376						
<b>_</b>									
	AX								
	AY							Î	
		·							
AZ L				2	Additional References sheet(s) attached				
Examiner Date Considered /									
Examiner		bre a strong	X / I	111700	Date Co	nsidered	10 11	20 2 () II	
Examiner		presta	XIU	Acitation in In academy and with MISSES	.1			0204	
*Examiner: Ir	nitial if n	eference is considered,	whether or no opy of this form	t citation is in conformance with MPEP 6 n with next communication to applicant.	.1				

**A**